



TEST REPORT

Report Number: R15701621-E13d

Applicant : HID Global Corp
611 Center Ridge Dr.
Austin, TX 78753, USA

Model : 40KV2

FCC ID : JQ6-SIGNO40KV2

IC : 2236B-SIGNO40KV2

EUT Description : Signo V2 Reader

Test Standard(s) : FCC 47 CFR PART 1 SUBPART I
FCC 47 CFR PART 2 SUBPART J
OET BULLETIN NO. 65
IEEE C95.3 – 2021
ISED RSS-102 Issue 6

Date Of Issue:

2025-07-01

Prepared by:

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Revision History

Rev.	Issue Date	Revisions	Revised By
V1	2025-06-12	Initial Issue	Chandler Stanley
V2	2025-07-01	Revised tables on pages 14 and 15	Chandler Stanley

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1. ATTESTATION OF TEST RESULTS

COMPANY NAME: HID Global Corp
611 Center Ridge Dr.
Austin, TX 78753, USA

EUT DESCRIPTION: Signo V2 Reader

MODEL: 40KV2

SERIAL NUMBER: FL0P0U013NWO40KTKF8087

SAMPLE RECEIPT DATE: 2025-03-10

DATE TESTED: 2025-03-18 and 2025-03-20

APPLICABLE STANDARDS	
STANDARD	TEST RESULTS
IEEE C95.3-2021	Complies
OET BULLETIN NO. 65	Complies
FCC 47 CFR PART 1 SUBPART I & PART 2 SUBPART J	Complies
ISED RSS-102 Issue 6	Complies

UL LLC tested the above equipment in accordance with the requirements set forth in the above standards. The test results show that the equipment tested is capable of demonstrating compliance with the requirements as documented in this report.

The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein. It is the manufacturer's responsibility to assure that additional production units of this model are manufactured with identical electrical and mechanical components. All samples tested were in good operating condition throughout the entire test program. Measurement Uncertainties are published for informational purposes only and were not taken into account unless noted otherwise.

This document may not be altered or revised in any way unless done so by UL LLC and all revisions are duly noted in the revisions section. Any alteration of this document not carried out by UL LLC will constitute fraud and shall nullify the document.

Approved & Released For
UL LLC By:



Sarah Kuhaneck
Engineer Project Associate
Consumer, Medical and IT Segment
UL LLC

Reviewed By:



Chandler Stanley
Engineer
Consumer, Medical and IT Segment
UL LLC

2. TEST METHODOLOGY

This report contains data provided by the customer which can impact the validity of results. UL LLC is only responsible for correctly integrating customer-provided data with measurements performed by UL LLC.

All testing / calculations were made in accordance with.

- FCC KDB 447498 D01 General RF Exposure Guidance v06
- FCC KDB 447498 D03 Supplement C Cross-Reference v01
- FCC Parts 1.1310, 2.1091, 2.1093, IEEE Std C95.1-2005, IEEE Std C95.3-2021
- RSS-102 Issue 6
- IC Safety Code 6

3. FACILITIES AND ACCREDITATION

UL LLC is accredited by A2LA, certification # 0751.06, for all testing performed within the scope of this report. Testing was performed at the locations noted below.

	Address	ISED CABID	ISED Company Number	FCC Registration
<input type="checkbox"/>	Building: 12 Laboratory Dr RTP, NC 27709, U.S.A	US0067	2180C	825374
<input checked="" type="checkbox"/>	Building: 2800 Perimeter Park Dr. Suite B Morrisville, NC 27560, U.S.A		27265	

4. DECISION RULES AND MEASUREMENT UNCERTAINTY (RF EXPOSURE)

4.1. METROLOGICAL TRACEABILITY

All test and measuring equipment utilized to perform the tests documented in this report are calibrated on a regular basis, with a maximum time between calibrations of one year or the manufacturers' recommendation, whichever is less, and where applicable is traceable to recognized national standards.

4.2. DECISION RULES

The Decision Rule is based on Simple Acceptance in accordance with ISO Guide 98-4:2012 Clause 8.2. (Measurement uncertainty is not taken into account when stating conformity with a specified requirement.)

4.3. MEASUREMENT UNCERTAINTY

Where relevant, the following measurement uncertainty levels have been estimated for tests performed on the apparatus:

PARAMETER	U_{Lab}
Magnetic Field Reading (A/m)	+/-0.3 dB
Electric Field Reading (V/m)	+/-0.3 dB

Uncertainty figures are valid to a confidence level of 95.45%.

5. EQUIPMENT UNDER TEST

5.1. DESCRIPTION OF EUT

The EUT is a smartcard reader typically installed near doorway as part of physical access system, to control access to that door, and it contains BLE, 13.56 MHz RFID, and 125 kHz RFID radios. This report covers the RF exposure testing of the 13.56 MHz RFID radio.

5.2. SOFTWARE AND FIRMWARE

Firmware Version: 10.1

Hardware Version: Rev H

5.3. WORST-CASE CONFIGURATION AND MODE

The following configurations were tested as worst-case position:

Config	Descriptions	Frequency
1	Tag Off	13.56 MHz
2	Tag On (Centered)	
3	(Offset to WC Positioning)	

Additionally, testing in five orientations at each of the three configurations were performed. These include edge top, edge right, edge left, edge bottom and front. Only the worst-case data per configuration is included in the report.

5.4. DESCRIPTION OF TEST SETUP

SUPPORT TEST EQUIPMENT						
Description		Manufacturer	Model	Serial Number		FCC ID/DoC
Badge 13.56MHz		NXP Semiconductors	NA	NA		NA
I/O CABLES (RADIATED EMISSIONS)						
Cable No.	Port	# of Identical Ports	Connector Type	Cable Type	Cable Length (m)	Remarks
1	DC	1	10pin proprietary	Unshielded	<3m	Used to connect EUT to DC Power Supply.

5.5. MEASUREMENT SETUP

The measurements were taken using a probe placed 20 cm surrounding the device for all configurations.

20cm distance E-field and H-field are evaluated from the center of the Narda probe.

For measurement setup and all testing photos, refer to external photos exhibit R15701621-EP4d.

6. TEST AND MEASUREMENT EQUIPMENT

The following test and measurement equipment was used for the tests documented in this report:

Test Equipment Used (Morrisville – Conducted 1)

Test Equipment List					
Description	Manufacturer	Model	Label ID	Cal Due	Cal Date
Electric and Magnetic Field Probe	Narda	EHP-200AC	FA0001	2025-08-19	2024-08-19
Spectrum Analyzer	Keysight Technologies	N9030A	90411	2025-08-01	2024-08-01
NFC Probe Kit	EMCO	7405-9911-4442	NA	NA	NA
Antenna Port Software	UL	Version 2024.2.23	SOFTEMI	NA	NA
DC Power Supply	CircuitSpecialists.com	CSI3005X5	76021	NA	NA

7. DUTY CYCLE

LIMITS

None; for reporting purposes only.

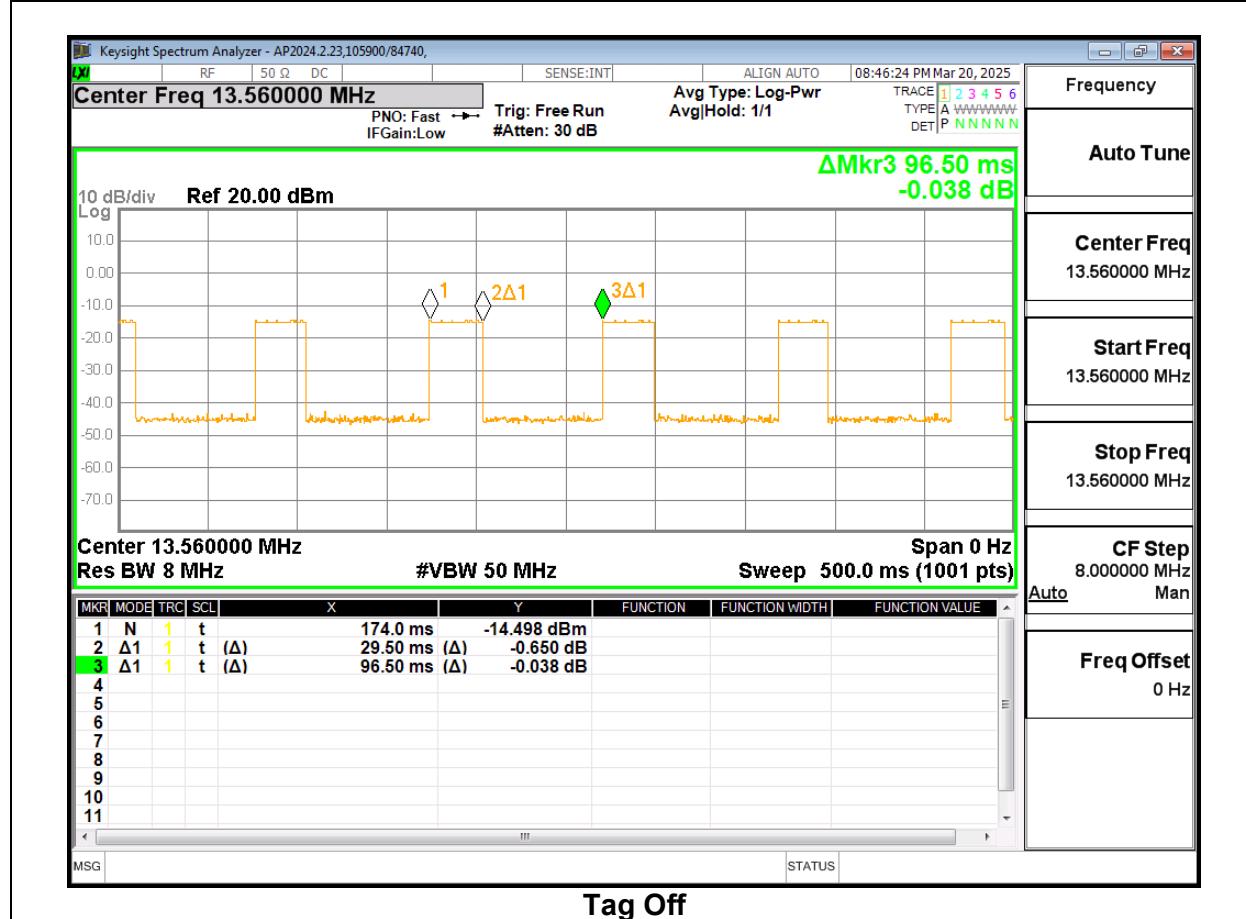
PROCEDURE

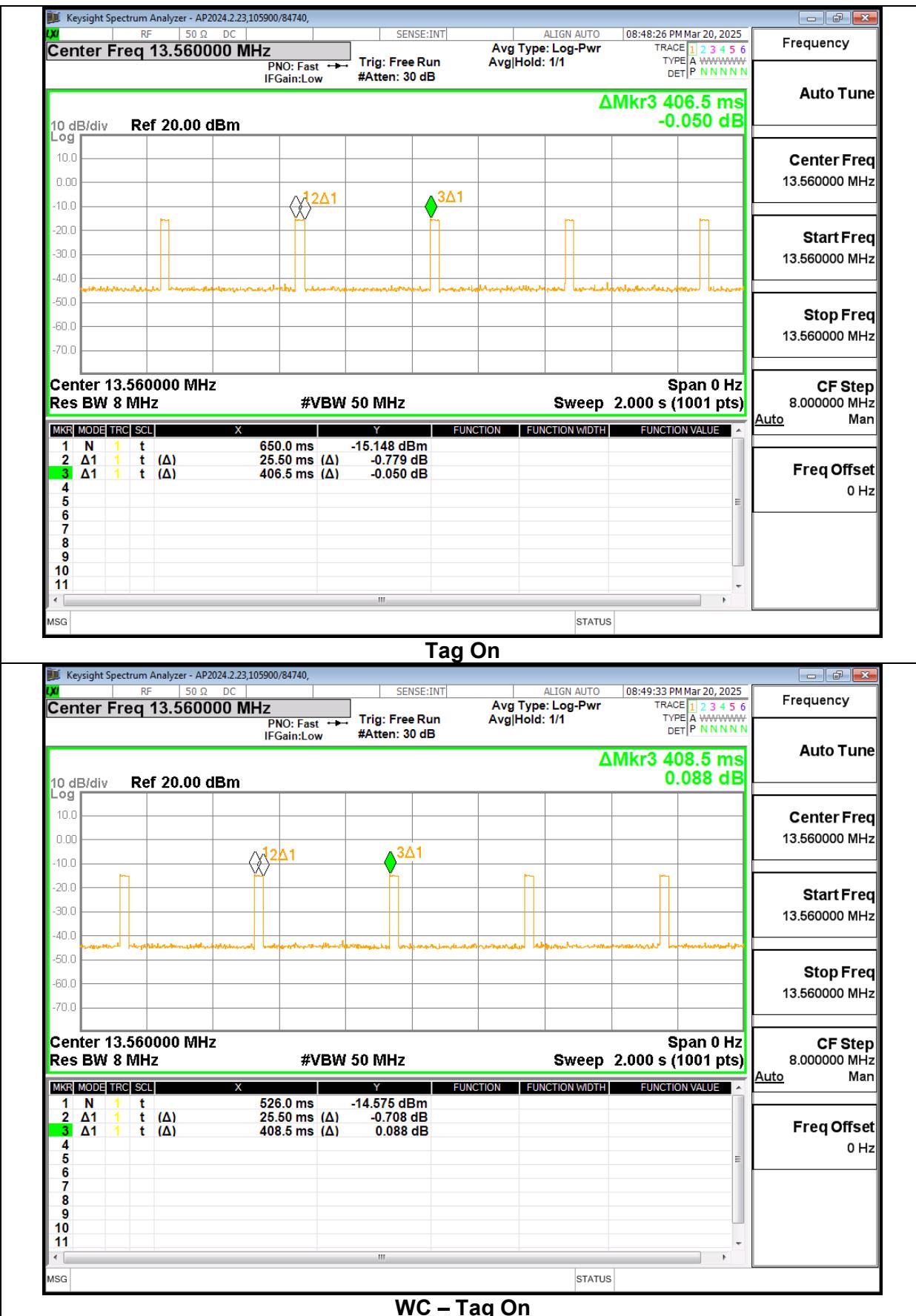
Zero-Span Spectrum Analyzer Method.

ON TIME AND DUTY CYCLE RESULTS

Test Engineer:	105900/84740
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Configuration	Frequency (MHz)	ON Time B (msec)	Period (msec)	Duty Cycle x (linear)	Duty Cycle (%)	Duty Cycle Correction Factor (dB)
1	13.56	29.50	96.50	0.31	30.57	NA
2	13.56	25.50	406.50	0.06	6.27	NA
3	13.56	25.50	408.50	0.06	6.24	NA





8. MAXIMUM PERMISSIBLE RF EXPOSURE

8.1. FCC LIMITS AND SUMMARY

§1.1310 The criteria listed in Table 1 shall be used to evaluate the environmental impact of human exposure to radiofrequency (RF) radiation as specified in §1.1307(b), except in the case of portable devices which shall be evaluated according to the provisions of §2.1093 of this chapter.

Table 1 to § 1.1310(e)(1) - Limits for Maximum Permissible Exposure (MPE)

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm ²)	Averaging time (minutes)
(i) Limits for Occupational/Controlled Exposure				
0.3-3.0	614	1.63	*(100)	≤6
3.0-30	1842/f	4.89/f	*(900/f ²)	<6
30-300	61.4	0.163	1.0	<6
300-1,500			f/300	<6
1,500-100,000			5	<6
(ii) Limits for General Population/Uncontrolled Exposure				
0.3-1.34	614	1.63	*(100)	<30
1.34-30	824/f	2.19/f	*(180/f ²)	<30
30-300	27.5	0.073	0.2	<30
300-1,500			f/1500	<30
1,500-100,000			1.0	<30

f = frequency in MHz. * = Plane-wave equivalent power density.

Using the table above, the limits for uncontrolled exposure to 13.56 MHz RFID radio is 60.77 V/m and 0.16 A/m.

RESULT:

Test Engineer:	105900/84740	Test Date:	2025-03-18
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8.2. IC LIMITS

Radio Standards Specification 102, Issue 6 Radio Frequency (RF) Exposure Compliance of Radio communication Apparatus (All Frequency Bands), sets out the requirements and measurement techniques used to evaluate radio frequency (RF) exposure compliance of radio communication apparatus designed to be used within the vicinity of the human body

The electric and magnetic field strength reference levels, power density reference levels, and associated reference period for devices employed by the general public (uncontrolled environment) and controlled-use devices (controlled environment) are specified in table 7 and table 8. Note that the power density limits specified in these tables apply to whole body exposure conditions.

Table 7: RF field strength and power density limits for devices used by the general public (uncontrolled environment)

Frequency range (MHz)	Electric field (V _{RMS} /m)	Magnetic field (A _{RMS} /m)	Power density (W/m ²)	Reference period (minutes)
10-20	27.46	0.0728	2	6
20-48	58.07 / $f^{0.25}$	0.1540 / $f^{0.25}$	8.944 / $f^{0.5}$	6
48-300	22.06	0.05852	1.291	6
300-6000	3.142 $f^{0.3417}$	0.008335 $f^{0.3417}$	0.02619 $f^{0.6834}$	6
6000-15000	61.4	0.163	10	6
15000-150000	61.4	0.163	10	616000 / $f^{1.2}$
150000-300000	0.158 $f^{0.5}$	$4.21 \times 10^{-4} f^{0.5}$	$6.67 \times 10^{-5} f$	616000 / $f^{1.2}$

Note: f is frequency in MHz.

8.2.1. MAXIMUM RESULT SUMMARY RF EXPOSURE (FCC)

CONFIGURATION 1: TAG OFF

Electric Field			Magnetic Field		
FCC RF Exposure Limit (V/m)	Maximum Average (V/m)	Percentage (%)	FCC RF Exposure Limit (A/m)	Maximum Average (A/m)	Percentage (%)
60.77	5.2108	8.575	0.16	0.0609	38.063

CONFIGURATION 2: TAG ON (CENTERED)

Electric Field			Magnetic Field		
FCC RF Exposure Limit (V/m)	Maximum Average (V/m)	Percentage (%)	FCC RF Exposure Limit (A/m)	Maximum Average (A/m)	Percentage (%)
60.77	3.1120	5.121	0.16	0.0259	16.188

CONFIGURATION 3: TAG ON (OFFSET)

Electric Field			Magnetic Field		
FCC RF Exposure Limit (V/m)	Maximum Average (V/m)	Percentage (%)	FCC RF Exposure Limit (A/m)	Maximum Average (A/m)	Percentage (%)
60.77	3.4872	5.738	0.16	0.0246	15.375

8.2.2. MAXIMUM RESULT SUMMARY RF EXPOSURE (RSS 102)

CONFIGURATION 1: TAG OFF

Electric Field			Magnetic Field		
IC RF Exposure Limit (V/m)	Maximum Average (V/m)	Percentage (%)	IC RF Exposure Limit (A/m)	Maximum Average (A/m)	Percentage (%)
27.46	5.2108	18.976	0.0728	0.0609	83.654

CONFIGURATION 2: TAG ON (CENTERED)

Electric Field			Magnetic Field		
IC RF Exposure Limit (V/m)	Maximum Average (V/m)	Percentage (%)	IC RF Exposure Limit (A/m)	Maximum Average (A/m)	Percentage (%)
27.46	3.1120	11.333	0.0728	0.0259	35.577

CONFIGURATION 3: TAG ON (OFFSET)

Electric Field			Magnetic Field		
IC RF Exposure Limit (V/m)	Maximum Average (V/m)	Percentage (%)	IC RF Exposure Limit (A/m)	Maximum Average (A/m)	Percentage (%)
27.46	3.4872	12.699	0.0728	0.0246	33.791

8.2.3. E- FIELD AND H- FIELD MEASUREMENTS (FCC)

Note: Peak measurements were performed. RMS values were calculated from the peak measurement. Please refer to the formula for calculating the RMS values: [Field Strength x $\sqrt{\text{Duty Cycle}}$].

CONFIGURATION 1: TAG OFF

Configuration	Test Mode	Measuring Distance (cm)	Electric Field Limit (V/m)	Electric Field Reading (V/m)				Magnetic Field Limit (A/m)	Magnetic Field Reading (A/m)			
				FCC	Location	Peak	Duty Cycle %		FCC	Location	Peak	Duty Cycle %
1	NA	20	60.77	Top	7.1335	30.57	4.3406	0.16	Top	0.0266	30.57	0.0147
				Right	9.2362		5.1067		Right	0.0283	0.0156	
				Bottom	4.4833		2.4788		Bottom	0.0269	0.0149	
				Left	6.2459		3.4534		Left	0.0287	0.0159	
				Front	9.4244		5.2108		Front	0.1101	0.0609	
				Max	9.4244		5.2108		Max	0.1101	0.0609	

CONFIGURATION 2: TAG ON (CENTERED)

Configuration	Test Mode	Measuring Distance (cm)	Electric Field Limit (V/m)	Electric Field Reading (V/m)				Magnetic Field Limit (A/m)	Magnetic Field Reading (A/m)			
				FCC	Location	Peak	Duty Cycle %		FCC	Location	Peak	Duty Cycle %
2	NA	20	60.77	Top	7.8505	6.27	1.9658	0.16	Top	0.0287	6.27	0.0072
				Right	10.885		2.7256		Right	0.0298	0.0075	
				Bottom	8.9355		2.2374		Bottom	0.0281	0.0070	
				Left	8.5435		2.1393		Left	0.0300	0.0075	
				Front	12.428		3.1120		Front	0.1035	0.0259	
				Max	12.428		3.1120		Max	0.1035	0.0259	

CONFIGURATION 3: TAG ON (OFFSET)

Configuration	Test Mode	Measuring Distance (cm)	Electric Field Limit (V/m)	Electric Field Reading (V/m)				Magnetic Field Limit (A/m)	Magnetic Field Reading (A/m)			
				FCC	Location	Peak	Duty Cycle %		FCC	Location	Peak	Duty Cycle %
3	NA	20	60.77	Top	8.1181	6.24	2.0279	0.16	Top	0.0279	6.24	0.0070
				Right	10.263		2.5637		Right	0.0288	0.0072	
				Bottom	8.7162		2.1773		Bottom	0.0275	0.0069	
				Left	9.3641		2.3392		Left	0.0288	0.0072	
				Front	13.960		3.4872		Front	0.0984	0.0246	
				Max	13.960		3.4872		Max	0.0984	0.0246	

8.2.4. E- FIELD AND H- FIELD MEASUREMENTS (IC)

Note: Peak measurements were performed. RMS values were calculated from the peak measurement. Please refer to the formula for calculating the RMS values: [Field Strength x $\sqrt{\text{Duty Cycle}}$].

CONFIGURATION 1: TAG OFF

Configuration	Test Mode	Measuring Distance (cm)	Electric Field Limit (V/m)	Electric Field Reading (V/m)				Magnetic Field Limit (A/m)	Magnetic Field Reading (A/m)				
				IC	Location	Peak	Duty Cycle %	IC Average	IC	Location	Peak	Duty Cycle %	IC Average
1	NA	20	27.46	Top	7.1335		30.57	4.3406	0.0728	Top	0.0266	30.57	0.0147
				Right	9.2362			5.1067		Right	0.0283		0.0156
				Bottom	4.4833			2.4788		Bottom	0.0269		0.0149
				Left	6.2459			3.4534		Left	0.0287		0.0159
				Front	9.4244			5.2108		Front	0.1101		0.0609
				Max	9.4244			5.2108		Max	0.1101		0.0609

CONFIGURATION 2: TAG ON (CENTERED)

Configuration	Test Mode	Measuring Distance (cm)	Electric Field Limit (V/m)	Electric Field Reading (V/m)				Magnetic Field Limit (A/m)	Magnetic Field Reading (A/m)				
				IC	Location	Peak	Duty Cycle %	IC Average	IC	Location	Peak	Duty Cycle %	IC Average
2	NA	20	27.46	Top	7.8505		6.27	1.9658	0.0728	Top	0.0287	6.27	0.0072
				Right	10.885			2.7256		Right	0.0298		0.0075
				Bottom	8.9355			2.2374		Bottom	0.0281		0.0070
				Left	8.5435			2.1393		Left	0.0300		0.0075
				Front	12.428			3.1120		Front	0.1035		0.0259
				Max	12.428			3.1120		Max	0.1035		0.0259

CONFIGURATION 3: TAG ON (OFFSET)

Configuration	Test Mode	Measuring Distance (cm)	Electric Field Limit (V/m)	Electric Field Reading (V/m)				Magnetic Field Limit (A/m)	Magnetic Field Reading (A/m)				
				IC	Location	Peak	Duty Cycle %	IC Average	IC	Location	Peak	Duty Cycle %	IC Average
3	NA	20	27.46	Top	8.1181		6.24	2.0279	0.0728	Top	0.0279	6.24	0.0070
				Right	10.263			2.5637		Right	0.0288		0.0072
				Bottom	8.7162			2.1773		Bottom	0.0275		0.0069
				Left	9.3641			2.3392		Left	0.0288		0.0072
				Front	13.960			3.4872		Front	0.0984		0.0246
				Max	13.960			3.4872		Max	0.0984		0.0246

9. RF EXPOSURE TEST SETUP AND SETUP PHOTO

For measurement setup and all testing photos, refer to external photos exhibit R15701621-EP4d.

END OF REPORT